

nanoFAB Online Sample Submission Procedure

March 2017

nanoFAB

Laboratory Management & Access Control System (LMACS)

Manage ▾

Facility ▾

Equipment ▾

Photomasks

Requests

Tasks

Requests

Currently Logged In

Facility Notices

Create Reservation

1. Log onto LMACS
2. Click “Requests” button

3. Fill in general information

- Select Type – ***“Sample”***
- Indicate whether you like samples to be returned or not upon completion of analysis.
- Click ***“Create Request”*** button

The screenshot displays the nanoFAB LMACS interface. At the top, the University of Alberta logo is on the left, and navigation links for 'Find a Person', 'ONEcard', 'Bear Tracks', 'Maps', and 'Email & Apps' are on the right. Below this is a green header bar with 'nanoFAB' and 'Laboratory Management & Access Control System (LMACS)'. A dark navigation bar contains links for 'Manage', 'Facility', 'Equipment', 'Photomasks', and 'Requests'. The main content area is titled 'Submit a New Request' with a 'Manage Requests' button on the right. The form includes a 'Title' field with 'XPS analysis.', a 'Select Project' dropdown with 'Nanofab.Process_Development', a 'Select Type' dropdown with 'Sample' (highlighted with a red box), and a 'Select Equipment (optional)' dropdown with 'XPS Imaging Spectrometer (Kratos AXIS Ultra)'. A 'Summary' text area contains the text 'I would like to submit 4 samples for XPS analysis.'. Below this is a 'Return any samples' checkbox (highlighted with a red box) which is currently unchecked. A yellow informational box states 'You can attach additional information (files/steps..) in the next step'. At the bottom right, a 'Create Request' button is highlighted with a red box.

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Requests

Submit a New Request

Manage Requests

That's it!

You've completed the minimum information required to get started. If you would like to add additional information to your request, you can click the "Edit Request" button. You can also view / edit your other pending requests from the list below.

Edit Request

Pending Requests

14 results

Title	Submitted	Modified	Status
XPS analysis. Sample	Mar 5th	Mar 5th	Submitted

4. Click “*Edit Request*” to add detailed description of samples and analysis.

5. Edit sample details in “Add items” session:

- One sample per item
- Sample name in Label
- Select “**Sample**” type
- Add sample information and analysis details in “*description*”
- Click “Add Item”

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Laboratory Management & Access Control System (LMACS)

Manage

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Requests

Peng LiAdmin?

XPS analysis.

Submitted by: Peng Li

Request ID: 2172

Item Details0

Empty
No items have been added to this request yet.

Comments0

add your comment...

Add Commentprivate

History2

Mar 5, 2017 10:04pmPeng Li changed Assigned To From: nobody To: Peng Li

Mar 5, 2017 10:04pmPeng Li initially created this request.

SummarySubmitted

Add Item(s)

Label
SiO2 nanoparticles (####)

Type
Sample


Select Equipment (if applicable)
XPS Imaging Spectrometer (Kratos AXIS Ultra)


Due Date
optional due date

Assign To
Assign Users

Description
Survey scan and high resolution scan of Si and O.

Add Item

 UNIVERSITY OF
ALBERTA

 THE
nanoFAB
Fabrication | Characterization | Expertise

An environment designed for success.

6. Print your request after completing editing sample details.

- Click 
- Check “Item details”
- Click “Print Request”
- A PDF is generated

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Laboratory Management & Access Control System (LMACS)

Manage Facility Equipment Photomasks Requests Peng Li Admin ?

XPS analysis.
Request ID: 2172

Submitted by: Peng Li

Include

☐ Comments ☐ Files ☐ Bookings ☒ Item Details

Item Details 4

Label	Type	Description	Assigned	Resource
1 SiO2 nanoparticles (####)	Sample	Survey scan and high resolution scan of Si and O.	Peng Li	XPS Imaging Spectrometer (Kratos AXIS Ultra) <input type="button" value="Edit"/>
ID: 2172-1686 <input type="button" value="Submitted"/>				
2 TiO2 nanoparticles (####)	Sample	Survey scan and high resolution scan of Ti and O.	Peng Li	XPS Imaging Spectrometer (Kratos AXIS Ultra) <input type="button" value="Edit"/>
ID: 2172-1687 <input type="button" value="Submitted"/>				
3 TiO2 thin film (####)	Sample	Survey scan and high resolution scan of Ti and O a...	Peng Li	XPS Imaging Spectrometer (Kratos AXIS Ultra) <input type="button" value="Edit"/>
ID: 2172-1688 <input type="button" value="Submitted"/>				
4 TiO2 thin film (####)	Sample	Survey scan and high resolution scan of Ti and O a...	Peng Li	XPS Imaging Spectrometer (Kratos AXIS Ultra) <input type="button" value="Edit"/>
ID: 2172-1689 <input type="button" value="Submitted"/>				

Summary Submitted

Add Item(s)

Label
TiO2 thin film (###)

Type
Sample

Select Equipment (if applicable)
XPS Imaging Spectrometer (Kratos AXIS Ultra)

Due Date
optional due date

Assign To
Assign Users

Description
Sample: 20nm TiO2 film on Si substrate.

nanoFAB-request-....pdf

7. Print a hard copy and attach it to your samples

Please include your request ID and Item ID in any related communication with nanoFAB staff members.

nanoFAB Request Detail

Printed: Mar 5, 2017

Request ID: 2172

XPS analysis.

Project: Nanofab.Process_Development

Submitted By: Peng Li

Status: Submitted

Submitted Date: Mar 5, 2017

Type: Sample

Last Modified: Mar 5, 2017

Priority:

Due Date:

Equipment: XPS Imaging Spectrometer (Kratos AXIS Ultra)

Assigned To: Peng Li

Description: I would like to submit 4 samples for XPS analysis.

Items (4)

ID: 2172-1686: SiO2 nanoparticles (####) (Sample)

Equipment: XPS Imaging Spectrometer (Kratos AXIS Ultra)

Status: Submitted

Submitted: Mar 5, 2017

Survey scan and high resolution scan of Si and O.

ID: 2172-1687: TiO2 nanoparticles (####) (Sample)

Equipment: XPS Imaging Spectrometer (Kratos AXIS Ultra)

Status: Submitted

Submitted: Mar 5, 2017

Survey scan and high resolution scan of Ti and O.

ID: 2172-1688: TiO2 thin film (####) (Sample)

Equipment: XPS Imaging Spectrometer (Kratos AXIS Ultra)

Status: Submitted

Submitted: Mar 5, 2017

Survey scan and high resolution scan of Ti and O and depth profile measurement of Ti and O.

Sample: 10nm TiO2 film on Si substrate.

ID: 2172-1689: TiO2 thin film (####) (Sample)

Equipment: XPS Imaging Spectrometer (Kratos AXIS Ultra)

Status: Submitted

Submitted: Mar 5, 2017

Survey scan and high resolution scan of Ti and O and depth profile measurement of Ti and O.

Sample: 20nm TiO2 film on Si substrate.

Any samples submitted will be discarded. If you wish to have your samples returned, contact the nanoFAB

8. Files and Comments:

- Results will be uploaded in the “Files” session after completion of analysis.
- Users can upload related documents here
- Communication is best through “Comments” session.

Item Details 4

Label	Type	Description	Assigned	Resource
1 SiO2 nanoparticles (####)	Sample	Survey scan and high resolution scan of Si and O.	Peng Li	XPS Imaging Spectrometer (Kratos AXIS Ultra)
ID: 2172-1686				Submitted
2 TiO2 nanoparticles (####)	Sample	Survey scan and high resolution scan of Ti and O.	Peng Li	XPS Imaging Spectrometer (Kratos AXIS Ultra)
ID: 2172-1687				Submitted
3 TiO2 thin film (####)	Sample	Survey scan and high resolution scan of Ti and O a...	Peng Li	XPS Imaging Spectrometer (Kratos AXIS Ultra)
ID: 2172-1688				Submitted
4 TiO2 thin film (####)	Sample	Survey scan and high resolution scan of Ti and O a...	Peng Li	XPS Imaging Spectrometer (Kratos AXIS Ultra)
ID: 2172-1689				Submitted

Summary Submitted

Add Item(s)

Label

TiO2 thin film (####)

Type

Sample

Select Equipment (if applicable)

XPS Imaging Spectrometer (Kratos AXIS Ultra)

Due Date

optional due date

Assign To

Assign Users

Description

Sample: 20nm TiO2 film on Si substrate.

Add Item

Comments 0

add your comment...

You must have something to say

Files 0

Add File(s)

Drag & Drop Files